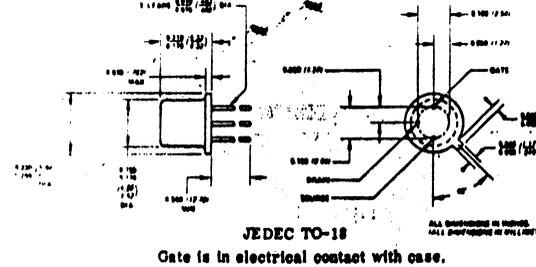


N-CHANNEL SILICON JUNCTION
FIELD-EFFECT TRANSISTORS

FOR SMALL-SIGNAL LOW-NOISE APPLICATIONS



PRODUCT CONDITIONING

Units receive the following treatment before final electrical tests:

High Temp Storage: 24 Hours at 150°C 25,000g Acceleration/Impact in the Y₁ Plane
Thermal Shock: +100 to 0°C for 5 Cycles Helium and/or Gross Leak Tests for Hermetic

*ABSOLUTE MAXIMUM RATINGS (25°C)

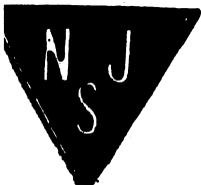
Gate-Drain or Gate-Source Voltage (Note 1)	-5
Gate Current	10
Total Device Dissipation at (or below) 25°C Free-Air Temperature (Note 2)	300
Storage Temperature Range	-65 to +20

*ELECTRICAL CHARACTERISTICS (25°C unless otherwise noted)

Characteristic	Test Conditions	2N3458		2N3459		2N3460		Units
		Min	Max	Min	Max	Min	Max	
I _{GSS}	Gate Reverse Current V _{GS} = -30 V, V _{DS} = 0		-0.25		-0.25		-0.25	nA
			-0.5		-0.5		-0.5	μA
BV _{DGR}	Drain-Gate Breakdown Voltage I _D = 1 μA, I _G = 0	-50		-50		-50		V
I _{D(GOFF)}	Drain Cutoff Current V _{DS} = 20 V, V _{GS} = (-1)		1 (-8)		1 (-4)		1 (-2)	nA (V)
V _P	Gate-Source Pinch-Off Voltage V _{DS} = 20 V, I _D = 1 μA		-7.8		-3.4		-1.8	V
I _{DSS}	Drain Current at Zero Gate Voltage V _{DS} = 20 V, V _{GS} = 0	3.0	15.0	0.8	4.0	0.2	1.0	mA
g _{fs}	Common-Source Forward Transconductance V _{DS} = 20 V, V _{GS} = 0, f = 1 kHz	2500	10,000	1500	6000	800	4500	μmhos
R _{oss}	Common-Source Output Conductance (Input Shorted) V _{DS} = 30 V, V _{GS} = 0, f = 1 MHz		35		20		5	μmhos
C _{oss}	Common-Source Output Capacitance (Input Shorted) V _{DS} = 30 V, V _{GS} = 0, f = 1 MHz		5		5		5	pF
C _{iss}	Common-Source Input Capacitance (Output Shorted) V _{GS} = 0, V _{DS} = (-1), f = 1 MHz		18 (10)		18 (6)		18 (4)	pF (V)
NF	Noise Figure V _{DS} = 10 V, V _{GS} = 0, f = 20 Hz, R _{gen} = 1 meg, BW = 4 Hz		6		4		4	dB

NOTES:

- Due to symmetrical geometry, these units may be operated with source and drain leads interchanged.
- Derate linearly to 200°C free-air temperature at rate of 1.7 mW/°C.
- JEDEC registered data.



NJ Semi-Conductors reserves the right to change test conditions, parameter limits and package dimensions without notice. Information furnished by NJ Semi-Conductors is believed to be both accurate and reliable at the time of going to press. However NJ Semi-Conductors assumes no responsibility for any errors or omissions discovered in its use. NJ Semi-Conductors encourages customers to verify that datasheets are current before placing orders.